

Automated identification of application-dependent safe faults in automotive systems-on-a-chips

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Combining fault analysis technologies for ISO26262 functional safety verification

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Determined-safe faults identification : a step towards ISO26262 hardware compliant designs

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri**; Sartoni, Sandro; Cantoro, Riccardo; Sonza Reorda, Matteo; Hamdioui, Said; Sauer, Christian 2020 25th IEEE European Test Symposium (ETS) 2020 / 6 p. : ill <https://doi.org/10.1109/ETS48528.2020.9131568>

Efficient methodology for ISO26262 functional safety verification

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri**; Hamdioui, Said; Sauer, Christian 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS), 1-3 July 2019, Rhodes, Greece 2019 / p. 255-256
<https://doi.org/10.1109/IOLTS.2019.8854449>

Improving the confidence level in functional safety simulation tools for ISO 26262

Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sauer, Christian 2018 Design and Verification Conference (DVCON) Europe : [proceedings] 2018 / 6 p. : ill <https://dvcon-proceedings.org/document/improving-the-confidence-level-in-functional-safety-simulation-tools-for-iso-26262/> <https://zenodo.org/record/3361607#.Y0PHFnZByHs>

Use of formal methods for verification and optimization of fault lists in the scope of ISO26262

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri**; Hamdioui, Said; Sauer, Christian 2018 Design and Verification Conference (DVCON) Europe : [proceedings] 2018 / 6 p. : ill <https://repository.tudelft.nl/islandora/object/uuid%3Adbd7f22d-0324-45f5-9180-8fe3fc95a9ce>